TEM Lattice Calculator Documentation

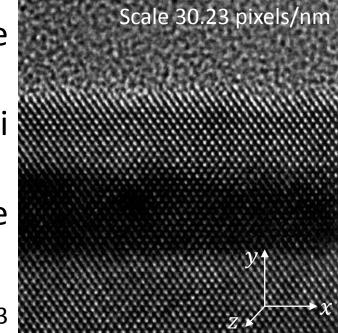
Jamie Teherani 5/16/2013

Oxide

Example Input Strained-Si

Strained-Ge

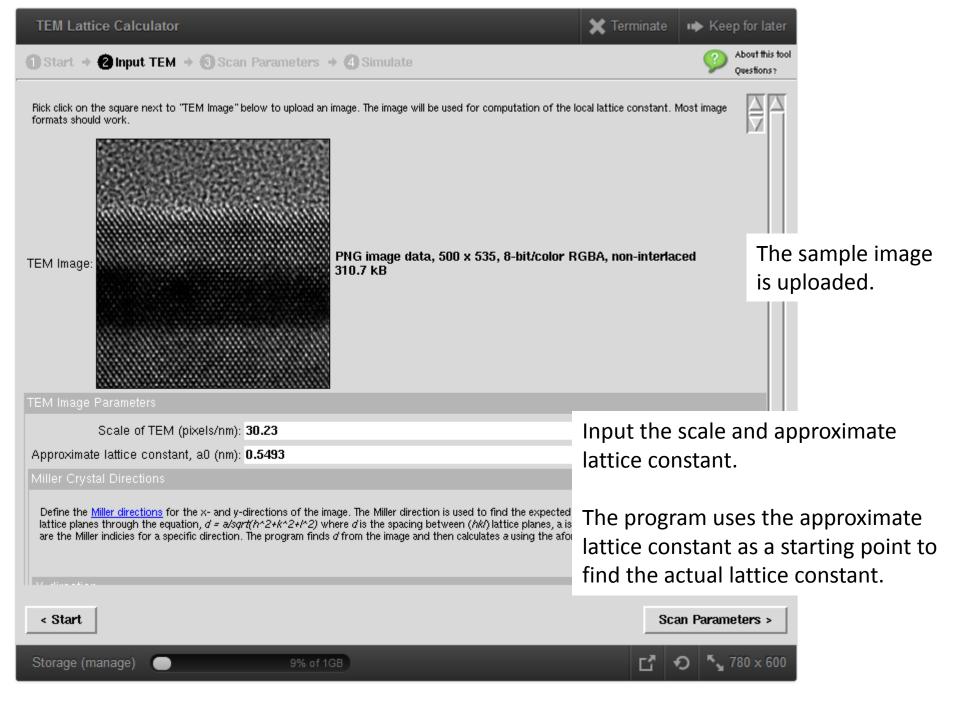
Relaxed Si_{0.7}Ge_{0.3}

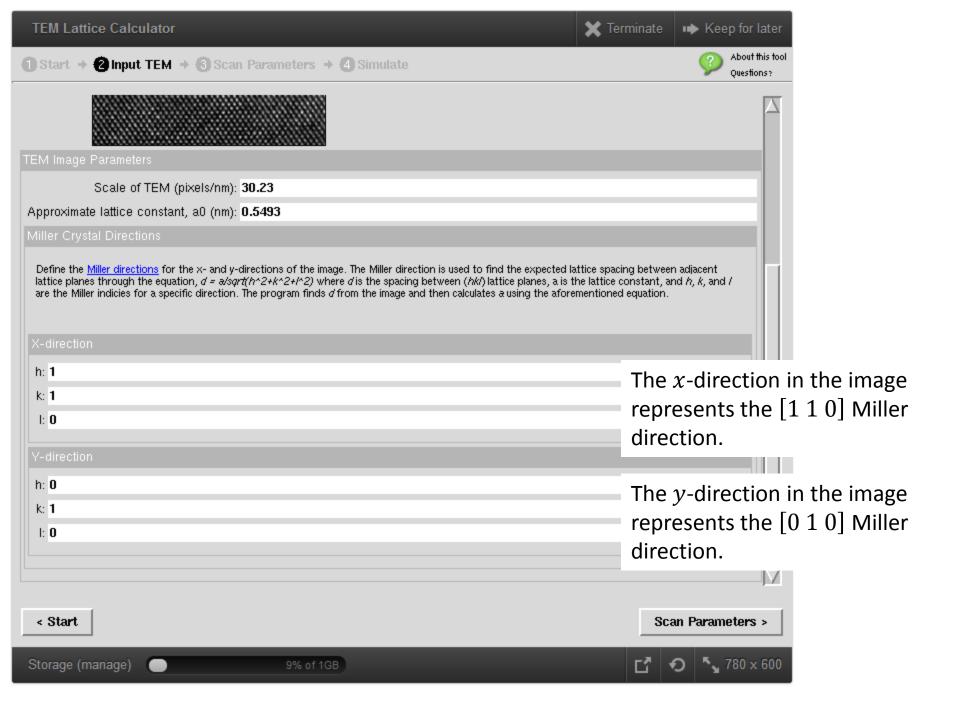


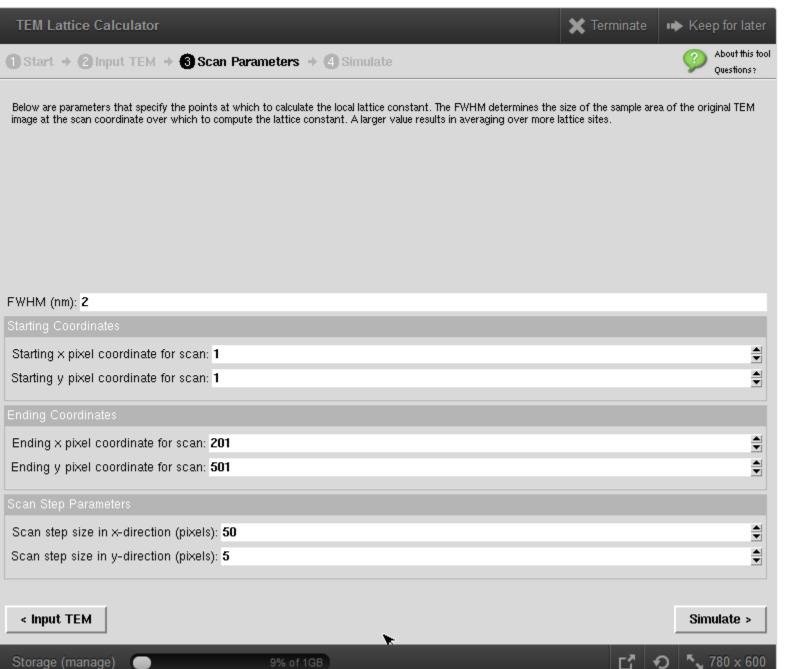
- File oxide_sSi_sGe_SiGe.png: high resolution TEM image of an epitaxially grown heterostructure of Si, Ge, and SiGe
- The SiGe is relaxed meaning that it has zero strain in all 3 lattice directions
- The Si and Ge layers are strained to the lattice constant of SiGe in the x- and z- direction, but not in the y- direction since it is a free surface.

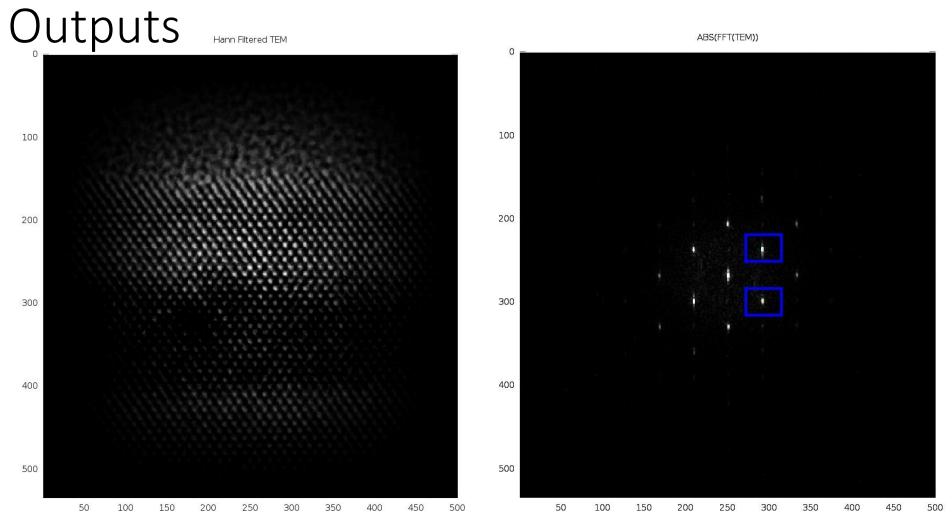
Strain and Lattice Constants

- Lattice constants, $a_{Si} = 0.5431$ nm, $a_{Ge} = 0.5658$ nm, $a_{Si_{0.7}Ge_{0.3}} = 0.5493$ nm
- Since the SiGe layer has a smaller lattice constant than Ge, the Ge is biaxially compressively strained in the *x-z* plane. This strain results in tensile strain in the *y*-direction due to Poisson's ratio.
- Since the SiGe layer has a larger lattice constant than Si, the Si is biaxially tensiley strained in the x-z plane. This strain results in compressive strain in the y-direction due to Poisson's ratio.



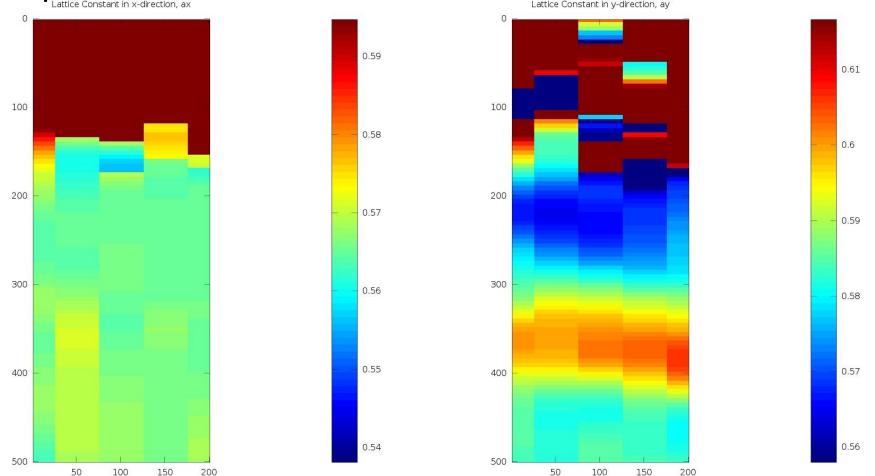






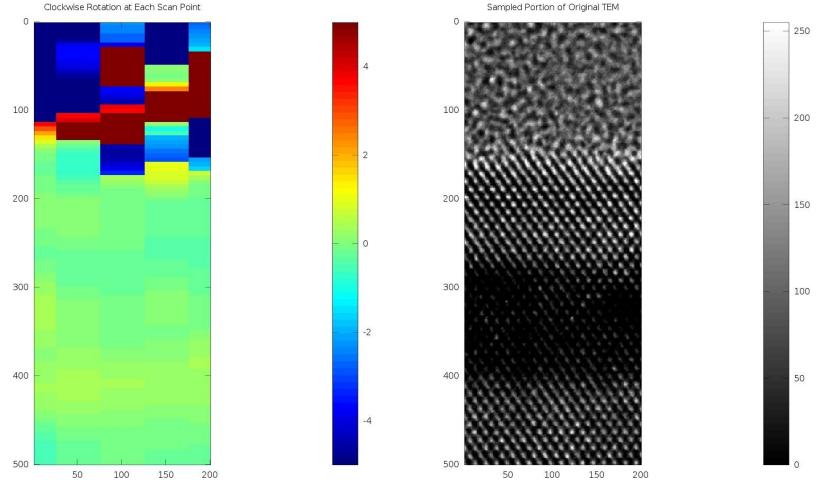
- Hann Filtered TEM: the original image with a Hann filter applied to it. The Hann filter is a sinusoidal function that decays to 0 at the edges of the image to reduce noise in the FFT.
- ABS(FFT(TEM)): the absolute value of the 2D Fourier transform of the Hann Filtered TEM. The
 blue boxes represent the areas over which the program searches for a maximum. The
 location of the maximum is related to the lattice constant. Zooming in reveals a red + and
 blue and green circles. The red + indicates the location of the approximate lattice constant
 entered in the input. The green and blue circles indicate the location of the actual maxima.

Outputs



- Lattice Constant in x-direction, ax: the lattice constant in the x-direction as a function of position in the image. The lattice constant in the x-direction is maintained in all the layers except the oxide, which is amorphous. Across the image, the average ax is ~0.565 nm which is quite large. This suggests that input value of image scale in pixels/nm should be adjusted to a slightly larger value such that $a_x \approx a_{Si_0, 7}Ge_{0,3}$.
- Lattice Constant in y-direction, ay: the y-directed lattice constant is seen to vary substantially across the layers due to the strain.

Outputs



- Clockwise Rotation at Each Scan Point: the calculate rotation as a function of position. The rotation is calculated from the maxima of the FFT of the image at each point of the scan.
- Sampled Portion of Original TEM: the portion of the original TEM image over which the scan was performed. It can be useful in creating an overlay.